

## 100344 Low Power 8-Bit Latch with Cut-Off Drivers

### General Description

The 100344 contains eight D-type latches, individual inputs ( $D_n$ ), outputs ( $Q_n$ ), a common enable pin ( $\overline{E}$ ), latch enable ( $\overline{LE}$ ), and output enable pin ( $\overline{OEN}$ ). A Q output follows its D input when both  $\overline{E}$  and  $\overline{LE}$  are LOW. When either  $\overline{E}$  or  $\overline{LE}$  (or both) are HIGH, a latch stores the last valid data present on its D input prior to  $\overline{E}$  or  $\overline{LE}$  going HIGH.

A HIGH on  $\overline{OEN}$  holds the outputs in a cut-off state. The cut-off state is designed to be more negative than a normal ECL LOW level. This allows the output emitter-followers to turn off when the termination supply is  $-2.0V$ , presenting a high impedance to the data bus. This high impedance reduces termination power and prevents loss of low state noise margin when several loads share the bus.

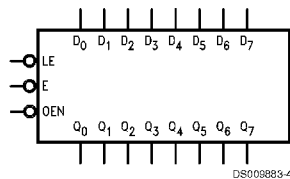
The 100344 outputs are designed to drive a doubly terminated  $50\Omega$  transmission line ( $25\Omega$  load impedance). All inputs have  $50\text{ k}\Omega$  pull-down resistors.

### Features

- Cut-off drivers
- Drives  $25\Omega$  load
- Low power operation
- 2000V ESD protection
- Voltage compensated operating range =  $-4.2V$  to  $-5.7V$
- Available to MIL-STD-883

### Ordering Code:

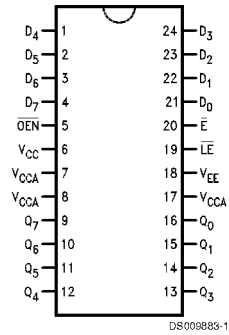
### Logic Symbol



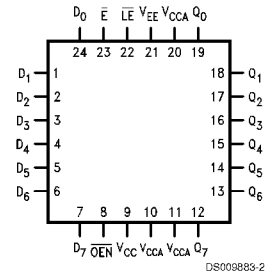
Pin Names	Description
$D_0$ – $D_7$	Data Inputs
$\overline{E}$	Enable Input
$\overline{LE}$	Latch Enable Input
$\overline{OEN}$	Output Enable Input
$Q_0$ – $Q_7$	Data Outputs

## Connection Diagrams

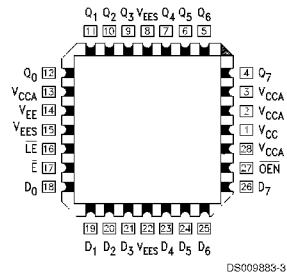
24-Pin DIP



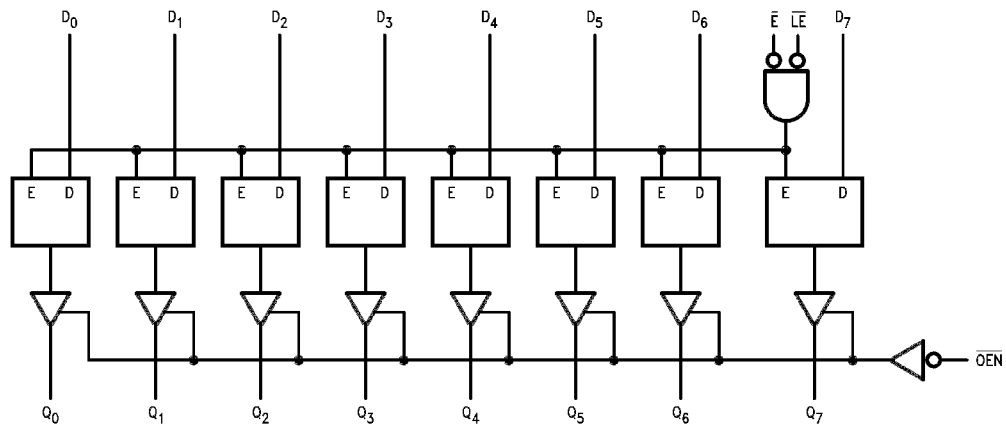
24-Pin Quad Cerpak



28-Pin PCC



## Logic Diagram



DS000883-5

## Truth Table

Inputs				Outputs
$D_n$	$\bar{E}$	$\bar{LE}$	$\bar{OEN}$	$Q_n$
L	L	L	L	L
H	L	L	L	H
X	H	X	L	Latched (Note 1)
X	X	H	L	Latched (Note 1)
X	X	X	H	Cutoff

H = HIGH Voltage level

L = LOW Voltage level

Cutoff = lower-than-LOW state

X = Don't Care

**Note 1:** Retains data present before either  $\bar{LE}$  or  $\bar{E}$  go HIGH.

## Absolute Maximum Ratings (Note 2)

Above which the useful life may be impaired

Storage Temperature ( $T_{STG}$ )	-65°C to +150°C
Maximum Junction Temperature ( $T_J$ )	
Ceramic	+175°C
Plastic	+150°C
$V_{EE}$ Pin Potential to Ground Pin	-7.0V to +0.5V
Input Voltage (DC)	$V_{EE}$ to +0.5V
Output Current (DC Output HIGH)	-100 mA
ESD (Note 3)	≥2000V

## Recommended Operating Conditions

Case Temperature ( $T_C$ )	
Commercial	0°C to +85°C
Industrial	-40°C to +85°C
Military	-55°C to +125°C
Supply Voltage ( $V_{EE}$ )	-5.7V to -4.2V

**Note 2:** Absolute maximum ratings are those values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

**Note 3:** ESD testing conforms to MIL-STD-883, Method 3015.

## Commercial Version

### DC Electrical Characteristics (Note 4)

$V_{EE} = -4.2V$  to  $-5.7V$ ,  $V_{CC} = V_{CCA} = GND$ ,  $T_C = 0^\circ C$  to  $+85^\circ C$

Symbol	Parameter	Min	Typ	Max	Units	Conditions
$V_{OH}$	Output HIGH Voltage	-1025	-955	-870	mV	$V_{IN} = V_{IH}$ (Max) Loading with or $V_{IL}$ (Min) 25Ω to -2.0V
$V_{OL}$	Output LOW Voltage	-1830	-1705	-1620	mV	
$V_{OHC}$	Output HIGH Voltage	-1035			mV	$V_{IN} = V_{IH}$ (Min) Loading with or $V_{IL}$ (Max) 25Ω to -2.0V
$V_{OLC}$	Output LOW Voltage			-1610	mV	
$V_{OLZ}$	Cutoff LOW Voltage			-1950	mV	$V_{IN} = V_{IH}$ (Min) or $V_{IL}$ (Max) $\overline{OEN} = HIGH$
$V_{IH}$	Input HIGH Voltage	-1165		-870	mV	Guaranteed HIGH Signal for All Inputs
$V_{IL}$	Input LOW Voltage	-1830		-1475	mV	Guaranteed LOW Signal for All Inputs
$I_{IL}$	Input LOW Current	0.50			μA	$V_{IN} = V_{IL}$ (Min)
$I_{IH}$	Input HIGH Current			240	μA	$V_{IN} = V_{IH}$ (Max)
$I_{EE}$	Power Supply Current	-178 -185		-85 -85	mA	Inputs Open $V_{EE} = -4.2V$ to $-4.8V$ $V_{EE} = -4.2V$ to $-5.7V$

**Note 4:** The specified limits represent the "worst case" value for the parameter. Since these values normally occur at the temperature extremes, additional noise immunity and guardbanding can be achieved by decreasing the allowable system operating ranges. Conditions for testing shown in the tables are chosen to guarantee operation under "worst case" conditions.

### DIP AC Electrical Characteristics

$V_{EE} = -4.2V$  to  $-5.7V$ ,  $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = 0^\circ C$		$T_C = +25^\circ C$		$T_C = +85^\circ C$		Units	Conditions
		Min	Max	Min	Max	Min	Max		
$t_{PLH}$	Propagation Delay	0.90	2.10	0.90	2.10	1.00	2.30	ns	Figures 1, 2 (Note 5)
$t_{PHL}$	$D_n$ to Output								
$t_{PLH}$	Propagation Delay	1.60	3.10	1.60	3.10	1.80	3.40	ns	Figures 1, 4 (Note 5)
$t_{PHL}$	$\overline{LE}$ , $\overline{E}$ to Output								
$t_{PZH}$	Propagation Delay	1.60	4.20	1.60	4.20	1.60	4.20	ns	Figures 1, 2 (Note 5)
$t_{PHZ}$	$\overline{OEN}$ to Output	1.00	2.70	1.00	2.70	1.00	2.70		
$t_{TLH}$	Transition Time	0.45	2.00	0.45	2.00	0.45	2.00	ns	Figures 1, 3
$t_{THL}$	20% to 80%, 80% to 20%								
$t_s$	Setup Time							ns	Figures 1, 3
	$D_0$ - $D_7$	1.00		1.00		1.10			
$t_H$	Hold Time							ns	Figures 1, 3
	$D_0$ - $D_7$	0.10		0.10		0.10			
$t_{pw(H)}$	Pulse Width HIGH							ns	Figures 1, 3
	$\overline{LE}$ , $\overline{E}$	2.00		2.00		2.00			

**Note 5:** The propagation delay specified is for single output switching. Delays may vary up to 300 ps with multiple outputs switching.

## PCC and Cerpak AC Electrical Characteristics

$V_{EE} = -4.2V$  to  $-5.7V$ ,  $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = 0^\circ C$		$T_C = +25^\circ C$		$T_C = +85^\circ C$		Units	Conditions
		Min	Max	Min	Max	Min	Max		
$t_{PLH}$ $t_{PHL}$	Propagation Delay $D_n$ to Output	0.90	1.90	0.90	1.90	1.00	2.10	ns	Figures 1, 2 (Note 7)
$t_{PLH}$ $t_{PHL}$	Propagation Delay $\overline{LE}$ , $\overline{E}$ to Output	1.60	2.90	1.60	2.90	1.80	3.20	ns	Figures 1, 4 (Note 7)
$t_{PZH}$ $t_{PHZ}$	Propagation Delay $\overline{OE}$ to Output	1.60	4.00	1.60	4.00	1.60	4.00	ns	Figures 1, 2 (Note 7)
$t_{TLH}$ $t_{THL}$	Transition Time 20% to 80%, 80% to 20%	0.45	1.90	0.45	1.90	0.45	1.90	ns	Figures 1, 3
$t_S$	Setup Time $D_0-D_7$	0.90		0.90		1.00		ns	Figures 1, 3
$t_H$	Hold Time $D_0-D_7$	0.00		0.00		0.00		ns	Figures 1, 3
$t_{pw(H)}$	Pulse Width HIGH $\overline{LE}$ , $\overline{E}$	2.00		2.00		2.00		ns	Figures 1, 3
$t_{OSHL}$	Maximum Skew Common Edge Output-to-Output Variation Data to Output Path		330		330		330	ps	PCC Only (Note 6)
$t_{OSLH}$	Maximum Skew Common Edge Output-to-Output Variation Data to Output Path		330		330		330	ps	PCC Only (Note 6)
$t_{OST}$	Maximum Skew Opposite Edge Output-to-Output Variation Data to Output Path		330		330		330	ps	PCC Only (Note 6)
$t_{ps}$	Maximum Skew Pin (Signal) Transition Variation Data to Output Path		230		230		230	ps	PCC Only (Note 6)

**Note 6:** Output-to-Output Skew is defined as the absolute value of the difference between the actual propagation delay for any outputs within the same packaged device. The specifications apply to any outputs switching in the same direction either HIGH to LOW ( $t_{OSHL}$ ), or LOW to HIGH ( $t_{OSLH}$ ), or in opposite directions both HL and LH ( $t_{OST}$ ). Parameters  $t_{OST}$  and  $t_{ps}$  guaranteed by design.

**Note 7:** The propagation delay specified is for single output switching. Delays may vary up to 300 ps with multiple outputs switching.

## Military Version

### DC Electrical Characteristics

$V_{EE} = -4.2V$  to  $-5.7V$ ,  $V_{CC} = V_{CCA} = GND$ ,  $T_C = -55^{\circ}C$  to  $+125^{\circ}C$

Symbol	Parameter	Min	Max	Units	$T_C$	Conditions	Notes	
$V_{OH}$	Output HIGH Voltage	-1025	-870	mV	$0^{\circ}C$ to $+125^{\circ}C$	$V_{IN} = V_{IH}$ (Max) or $V_{IL}$ (Min)	Loading with $25\Omega$ to $-2.0V$	(Notes 8, 9, 10)
		-1085	-870	mV	$-55^{\circ}C$			
$V_{OL}$	Output LOW Voltage	-1830	-1620	mV	$0^{\circ}C$ to $+125^{\circ}C$			
		-1830	-1555	mV	$-55^{\circ}C$			
$V_{OHC}$	Output HIGH Voltage	-1035		mV	$0^{\circ}C$ to $+125^{\circ}C$	$V_{IN} = V_{IH}$ (Min) or $V_{IL}$ (Max)	Loading with $25\Omega$ to $-2.0V$	(Notes 8, 9, 10)
		-1085		mV	$-55^{\circ}C$			
$V_{OLC}$	Output LOW Voltage		-1610	mV	$0^{\circ}C$ to $+125^{\circ}C$			
			-1555	mV	$-55^{\circ}C$			
$V_{OLZ}$	Cutoff LOW Voltage		-1950	mV	$0^{\circ}C$ to $+125^{\circ}C$	$V_{IN} = V_{IH}$ (MIN) or $V_{IL}$ (Max)	$\overline{OEN} = HIGH$	(Notes 8, 9, 10)
			-1850	mV	$-55^{\circ}C$			
$V_{IH}$	Input HIGH Voltage	-1165	-870	mV	$-55^{\circ}C$ to $+125^{\circ}C$	Guaranteed HIGH Signal for All Inputs	(Notes 8, 9, 10, 11)	
$V_{IL}$	Input LOW Voltage	-1830	-1475	mV	$-55^{\circ}C$ to $+125^{\circ}C$	Guaranteed LOW Signal for All Inputs	(Notes 8, 9, 10, 11)	
$I_{IL}$	Input LOW Current	0.50		$\mu A$	$-55^{\circ}C$ to $+125^{\circ}C$	$V_{EE} = -4.2V$ $V_{IN} = V_{IL}$ (Min)	(Notes 8, 9, 10, 11)	
$I_{IH}$	Input HIGH Current		240	$\mu A$	$0^{\circ}C$ to $+125^{\circ}C$	$V_{EE} = -5.7V$ $V_{IN} = V_{IH}$ (Max)	(Notes 8, 9, 10)	
			340	$\mu A$	$-55^{\circ}C$			
$I_{EE}$	Power Supply Current	-195	-65	mA	$-55^{\circ}C$ to $+125^{\circ}C$	Inputs Open $V_{EE} = -4.2V$ to $-4.8V$ $V_{EE} = -4.2V$ to $-5.7V$	(Notes 8, 9, 10)	
		-205	-65	mA				

**Note 8:** F100K 300 Series cold temperature testing is performed by temperature soaking (to guarantee junction temperature equals  $-55^{\circ}C$ ), then testing immediately without allowing for the junction temperature to stabilize due to heat dissipation after power-up. This provides "cold start" specs which can be considered a worst case condition at cold temperatures.

**Note 9:** Screen tested 100% on each device at  $-55^{\circ}C$ ,  $+25^{\circ}C$ , and  $+125^{\circ}C$ , Subgroups 1, 2, 3, 7, and 8.

**Note 10:** Sample tested (Method 5005, Table I) on each manufactured lot at  $-55^{\circ}C$ ,  $+25^{\circ}C$ , and  $+125^{\circ}C$ , Subgroups A1, 2, 3, 7, and 8.

**Note 11:** Guaranteed by applying specified input condition and testing  $V_{OH}/V_{OL}$ .

### AC Electrical Characteristics

$V_{EE} = -4.2V$  to  $-5.7V$ ,  $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = -55^{\circ}C$		$T_C = +25^{\circ}C$		$T_C = +125^{\circ}C$		Units	Conditions	Notes
		Min	Max	Min	Max	Min	Max			
$t_{PLH}$	Propagation Delay	0.50	2.60	0.70	2.60	0.70	3.10	ns	Figures 1, 2	(Notes 12, 13, 14, 16)
$t_{PHL}$	$D_n$ to Output									
$t_{PLH}$	Propagation Delay	0.80	3.30	1.00	3.30	1.10	3.80	ns	Figures 1, 4	(Notes 12, 13, 14, 16)
$t_{PHL}$	$\overline{LE}$ , $\overline{E}$ to Output									
$t_{PZH}$	Propagation Delay	1.00	4.60	1.10	4.20	1.20	4.40	ns	Figures 1, 2	(Notes 12, 13, 14, 16)
$t_{PHZ}$	$\overline{OEN}$ to Output	0.70	3.00	0.70	2.80	0.70	3.20			
$t_{TLH}$	Transition Time	0.40	2.50	0.40	2.40	0.40	2.70	ns	Figures 1, 3	(Note 15)
$t_{THL}$	20% to 80%, 80% to 20%									

## AC Electrical Characteristics (Continued)

$V_{EE} = -4.2V$  to  $-5.7V$ ,  $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = -55^\circ C$		$T_C = +25^\circ C$		$T_C = +125^\circ C$		Units	Conditions	Notes
		Min	Max	Min	Max	Min	Max			
$t_s$	Setup Time $D_0-D_7$	1.50		1.50		1.70		ns	Figures 1, 3	(Note 15)
$t_h$	Hold Time $D_0-D_7$	0.60		0.60		0.60		ns	Figures 1, 3	(Note 15)
$t_{pw(H)}$	Pulse Width HIGH $\overline{LE}, \overline{E}$	2.40		2.40		2.40		ns	Figures 1, 3	(Note 15)

**Note 12:** F100K 300 Series cold temperature testing is performed by temperature soaking (to guarantee junction temperature equals  $-55^\circ C$ ), then testing immediately after power-up. This provides "cold start" specs which can be considered a worst case condition at cold temperatures.

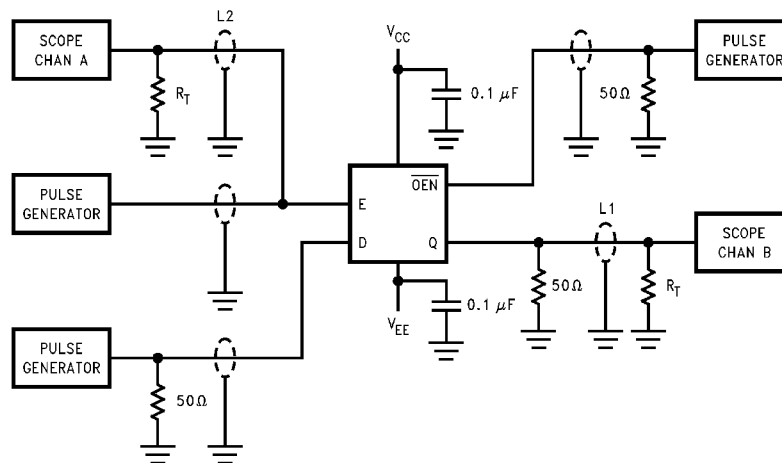
**Note 13:** Screen tested 100% on each device at  $+25^\circ C$  temperature only, Subgroup A9.

**Note 14:** Sample tested (Method 5005, Table I) on each manufactured lot at  $+25^\circ C$ , Subgroup A9, and at  $+125^\circ C$  and  $-55^\circ C$  temperatures, Subgroups A10 and A11.

**Note 15:** Not tested at  $+25^\circ C$ ,  $+125^\circ C$ , and  $-55^\circ C$  temperature (design characterization data).

**Note 16:** The propagation delay specified is for single output switching. Delays may vary up to 300 ps with multiple outputs switching.

## Test Circuitry



DS009883-6

### Notes:

$V_{CC}, V_{CCA} = +2V$ ,  $V_{EE} = -2.5V$

L1 and L2 = equal length  $50\Omega$  impedance lines

$R_T = 50\Omega$  terminator internal to scope

Decoupling  $0.1 \mu F$  from GND to  $V_{CC}$  and  $V_{EE}$

All unused outputs are loaded with  $25\Omega$  to GND

$C_L$  = Fixture and stray capacitance  $\leq 3$  pF

FIGURE 1. AC Test Circuit

## Switching Waveforms

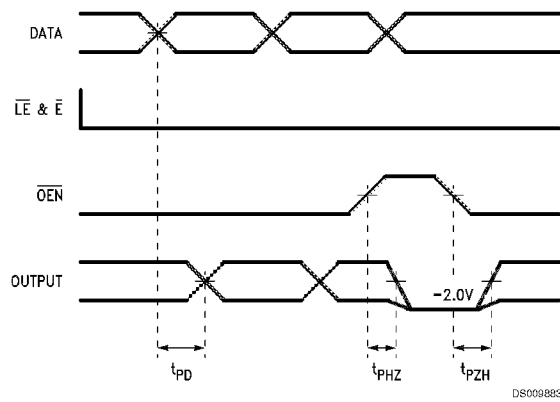


FIGURE 2. Propagation Delay and Cutoff Times

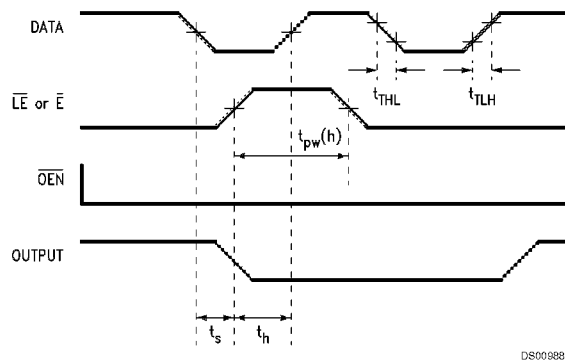


FIGURE 3. Setup, Hold and Pulse Width Times

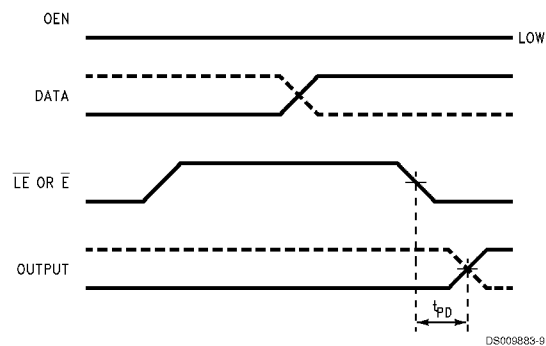
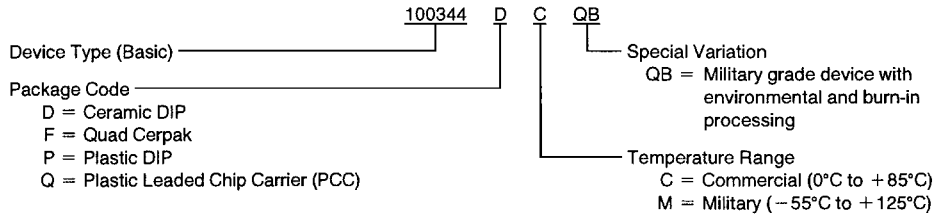


FIGURE 4. Propagation Delay  $\overline{LE}$ ,  $\overline{E}$  to Q



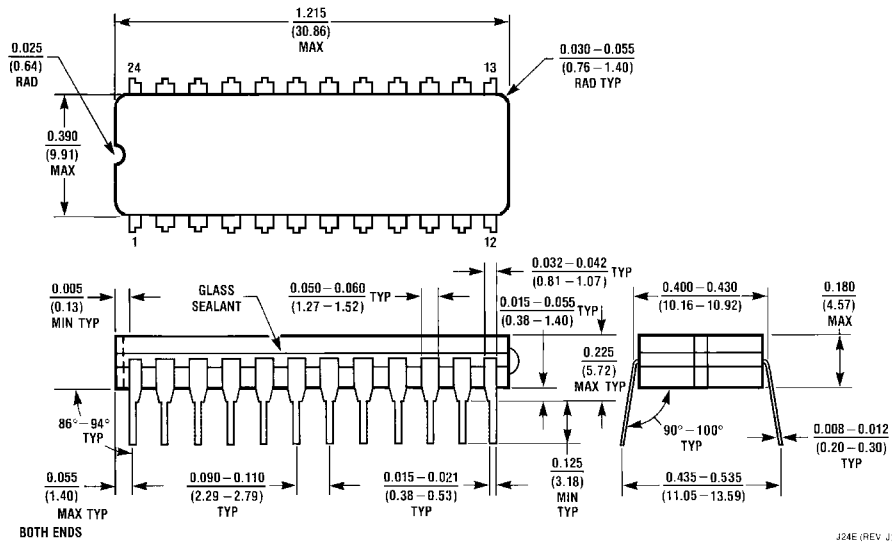
## Ordering Information

The device number is used to form part of a simplified purchasing code where a package type and temperature range are defined as follows:



DS009883-10

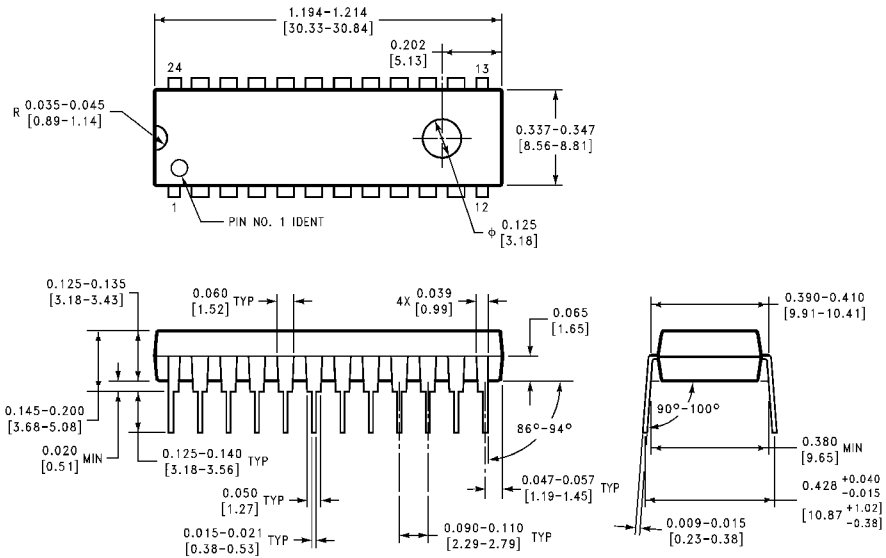
## Physical Dimensions inches (millimeters) unless otherwise noted



J24E (REV J)

24-Lead Ceramic Dual-In-Line Package (0.400" Wide) (D)  
Package Number J24E

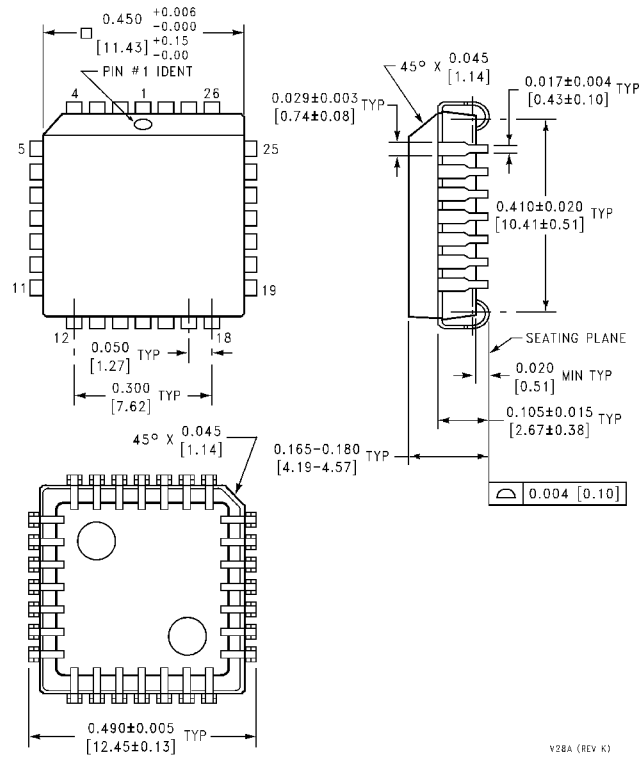
**Physical Dimensions** inches (millimeters) unless otherwise noted (Continued)



**24-Lead Plastic Dual-In-Line Package (P)**  
**Package Number N24E**

N24E (REV A)

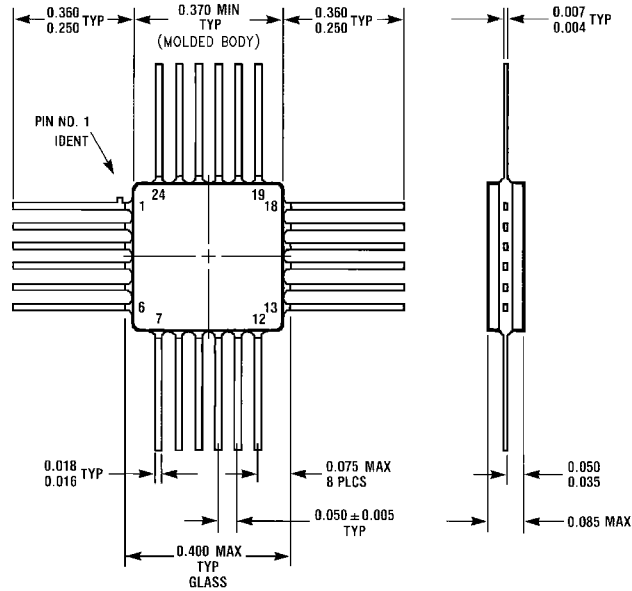
**Physical Dimensions** inches (millimeters) unless otherwise noted (Continued)



**28-Lead Plastic Chip Carrier (Q)  
Package Number V28A**

V28A (REV K)

**Physical Dimensions** inches (millimeters) unless otherwise noted (Continued)



W24B (REV D)

**24-Lead Quad Cerpak (F)  
Package Number W24B**

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